

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/788,615	MUKKER ET AL.		
Examiner	Art Unit		
Hong C. Kim	2185		

OFAROUER						
SEARCHED						
Class	Subclass	Date	Examiner			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
upon ser	5/18/06	ch		